

<b>Notice of References Cited</b>	Application/Control No. 10/749,958	Applicant(s)/Patent Under Reexamination DUBIN ET AL.	
	Examiner William T. Leader	Art Unit 1753	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,755,956	06-2004	Lee et al.	205/104
*	C	US-6,919,009	07-2005	Stonas et al.	205/74
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**NON-PATENT DOCUMENTS**

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	U	John L. Vossen et al, Thin Film Processes, Academic Press, New York, 1978, pp.212-218, 229-231.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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